

— 量子效率测试系统 · QUANTUM EFFICIENCY

IRDT-QE

系列探测器量子效率测试系统

IRDT-QE Series Detector Quantum Efficiency (QE) Test System

适用于可见光、短波、中波波段探测器量子效率检测，精准输出完整量子效率光谱曲线。系统测试精度优异、检测效率高，可清晰表征器件光谱选择响应能力，直观体现芯片掺杂、缺陷等材料固有特性；同时兼容量子效率、相对光谱、光子转移等多项检测功能。

The IRDT-QE series quantum efficiency test system measures visible, short-wave and mid-wave detectors, accurately generating complete QE spectral curves. It characterizes the spectral selective response of devices and reflects inherent material properties including chip doping and defects, and also supports relative spectrum and photon transfer tests.



IRDT-QE 量子效率测试系统

Quantum Efficiency / Relative Spectrum / Photon Transfer



0.4~5.0 μm

光谱范围

SPECTRAL RANGE

1nm

光谱分辨率

RESOLUTION

≤±5%

测试精度

TEST ACCURACY

**核心光学器件
顶尖供应商**

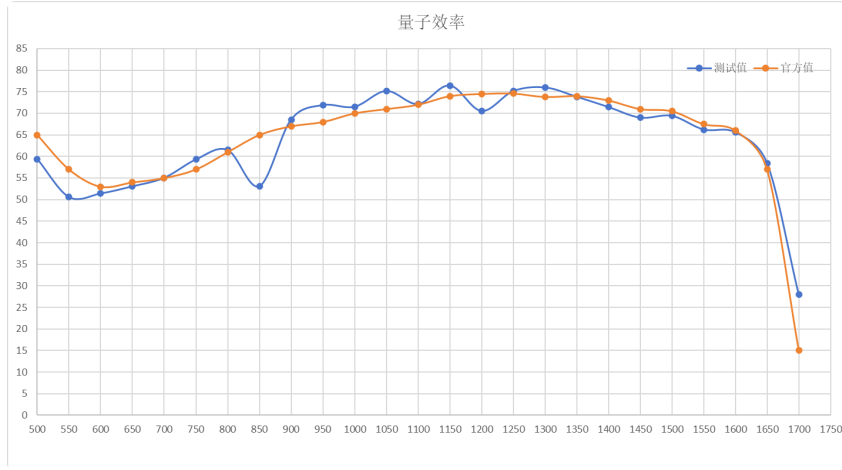
高效率 · 高可靠

FIRST-TIER SUPPLIERS

核心测试输出 · 量子效率曲线

短波 InSb 量子效率曲线 (QE)

测试值 vs 官方值



≈75%

峰值量子效率

Peak QE · 短波 SWIR

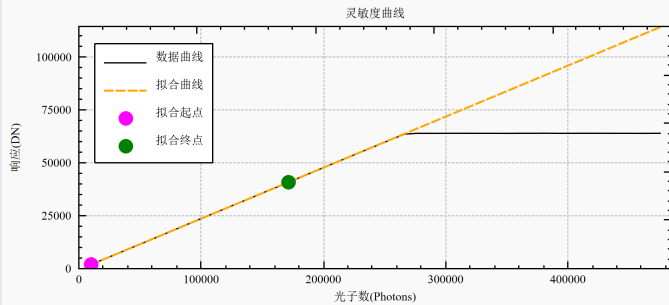
测试曲线与器件官方参考值在主要响应区间趋势高度一致，可准确表征器件光谱响应特性。

● 测试值 ≈ 官方值

灵敏度 & 光子转移曲线

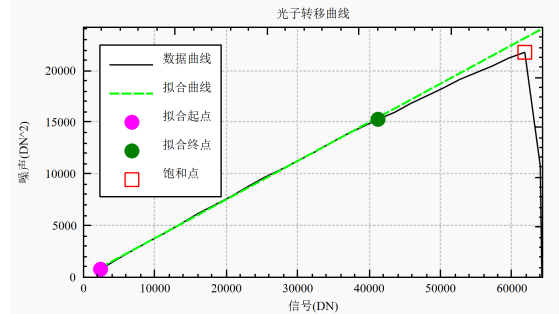
短波 InSb · 灵敏度曲线

Sensitivity



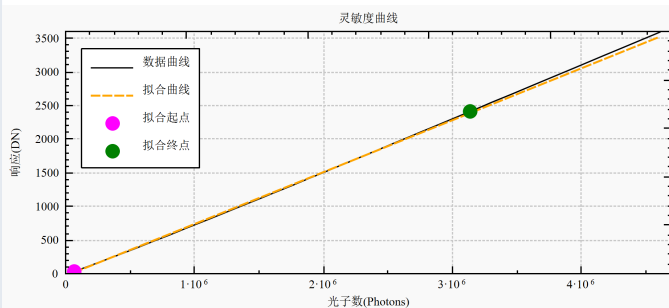
短波 InSb · 光子转移曲线

PTC



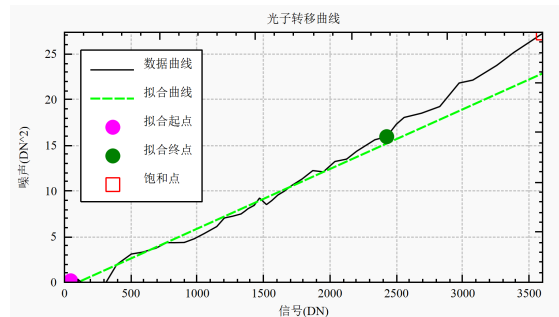
中波 MCT · 灵敏度曲线

Sensitivity



中波 MCT · 光子转移曲线

PTC



精准量子效率检测 · 一站式探测器表征

Precise QE measurement for infrared detector characterization

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